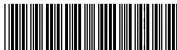


Search Notes**Application/Control No.**

10/537,329

Examiner

LOIS ZHENG

**Applicant(s)/Patent under
Reexamination**

NAKAYAMA ET AL.

Art Unit

1793

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship search	2/26/2008	LLZ
EAST search	2/28/2008	LLZ